

Enabling concepts: Packaging Technologies

Ana Collado / Liam Murphy
ESA / TEC-EDC

01/10/2018

Drivers for the future:

- Higher speed (>Gbps serial link)
- Higher integration between different active parts technologies
- Higher power dissipation
- Parts availability and market trends (e.g. Plastic parts, copper wire)
- Environmental regulation requirements (Lead free components)

Emerging Packaging Technologies for Space applications



Complexity



Plastic Ball Grid Array (PBGA): wire bonding on organic substrate



Flip-chip on ceramic



Plastic Ball Grid Array (PBGA): Flip-chip on organic substrate

Wafer Level Packaging: Fan-in or Fan Out WLP

2D & 2.5D packaging

3D Packaging

Maturity



Enabling concepts: Flip chip packaging

➤ Concept description:

- Could be done onto ceramic or organic substrate (e.g. PBGA)
- Different bumping solutions (SAC alloys, Cu pillar)

➤ Technology Benefits:

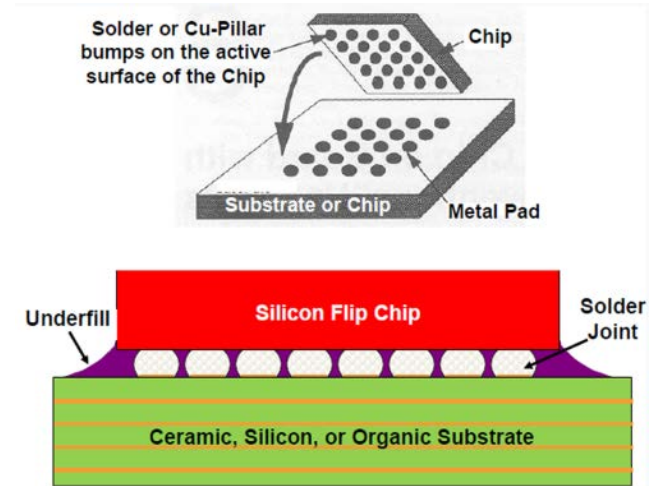
- Lower inductance than wire bonding
- Better bandwidth performance
- Lead free bumping (REACH compliant)

➤ Technology Drawbacks:

- Non-hermetic packages
- Little proven flight heritage

➤ Space acceptability:

- Extensive reliability testing related to Lead Free bumping and plastic packaging
- Establishment of procedures and requirements for manufacturing and test



Enabling concepts: Wafer Level Packaging

➤ Concept description:

- FI-WLP: Fan-in redistribution
- FO-WLP: Fan out redistribution with final molding

➤ Technology Benefits:

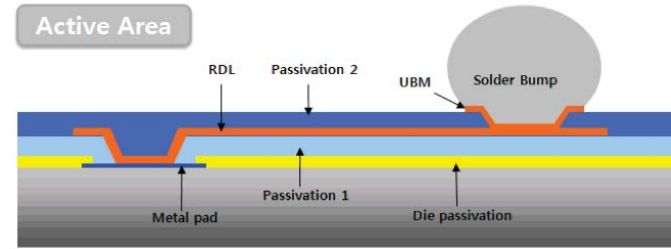
- Suitable for new sub-micron technologies (e.g. <28nm)
- Small Form Factor / Lower cost => High Drive from Mobile and IoT markets

➤ Technology Drawbacks:

- Dielectric strength /reliability of Redistribution Layers.
- Final encapsulation method is molded plastic (thermal management issues)

➤ Space acceptability:

- Lack of definition for testing of BEOL manufacturing
- Qualification approach similar to the silicon qualification



Enabling concepts: 2D / 2.5D Packaging

➤ Concept description:

- 2D / 2.5D Packaging (TSV).
- Silicon interposer, with or without TSVs. Different options/configurations possible

➤ Technology Benefits:

- Integration of different technologies (e.g. RF/ Digital)

➤ Technology Drawbacks:

- Use of Copper pillars with tin content > 97%
- Micro-copper pillars technology still evolving
- Complex testing procedures

➤ Space acceptability:

- High diversity of technologies and unknown reliability level (for Flight applications)

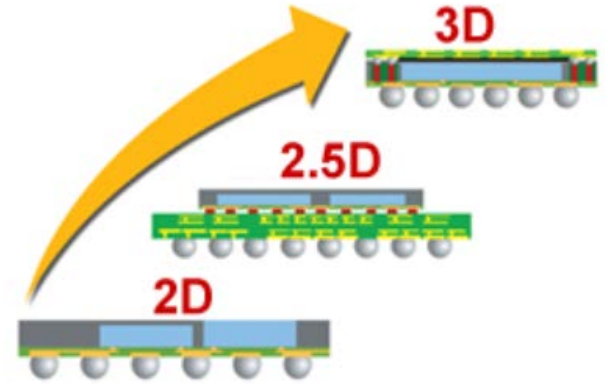


Fig. 1: Packaging solutions. Source STATS ChipPAC

Enabling concepts: 3D Packaging

➤ Concept description:

- Proven Tech: Stacked dies and Package-on-Package (PoP)
- Emerging Tech: 3D Wafer Stacking with TSV interconnects

➤ Technology Benefits:

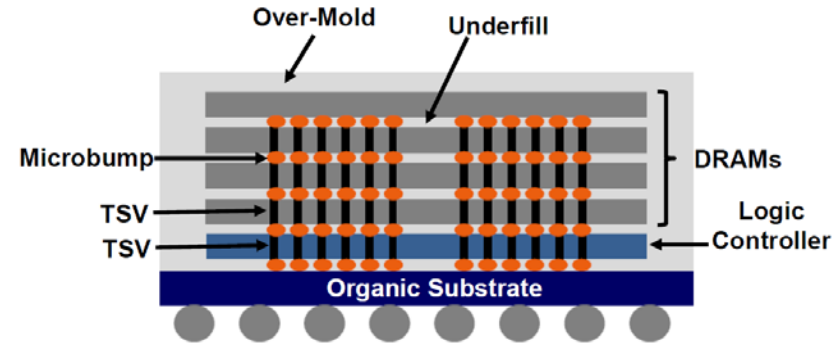
- Shorter-faster interconnections
- Solution for Memory on Logic

➤ Technology Drawbacks:

- Thermal management issues
- Micro-copper pillar & TSV technologies
- Limited shelf life (Moisture and solderability issues)

➤ Space acceptability:

- Complex Supply Chain. Qualification of both MEOL and BEOL processes



Conclusions



From the packaging perspective:

- Advanced packaging is perceived as a big variety of possible options in different maturity levels.
- Requirements flow down from components performance requirements/needs
- Reduced data available on space testing performed of Advanced Packaging
- Complex supply chain adds difficulty to the qualification of the product
- Advanced Packaging suppliers mainly in Far East
- Upcoming packaging materials restrictions (RoHs, REACH)

=> Could ESA use/qualify any of these technologies in the future?





APAC
2019

**Workshop on Advances in
Packaging and Components**

14-15th March 2019 | ESA-ESTEC | The Netherlands



CBGA:

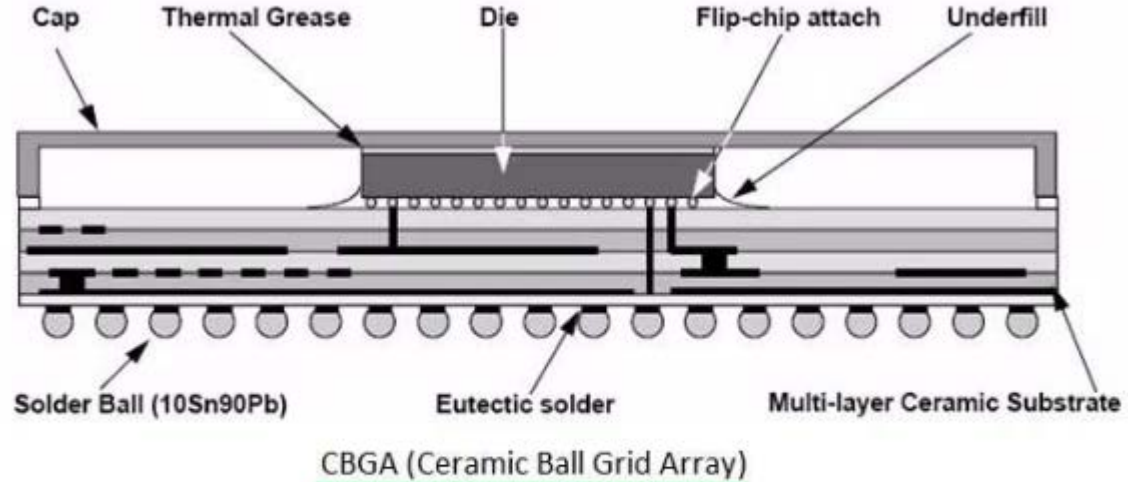


Image Cited from Test and Measurement World

Organic BGA:

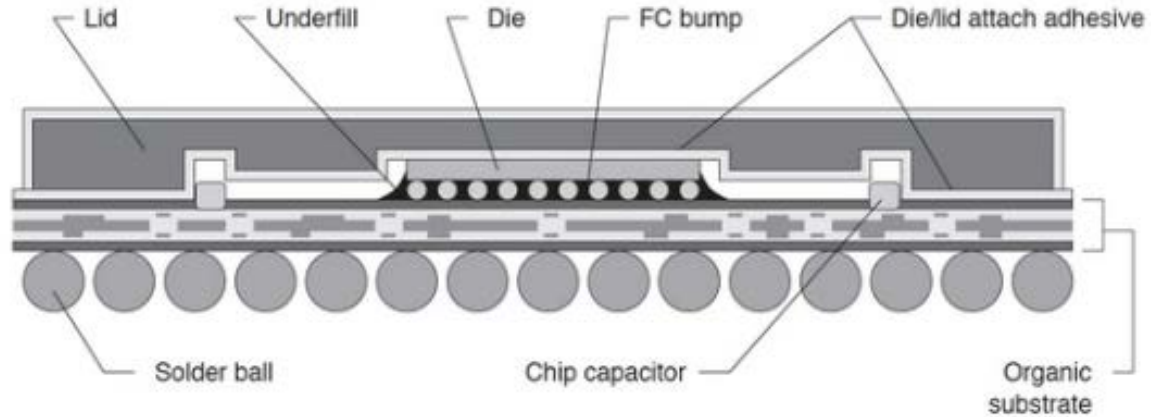
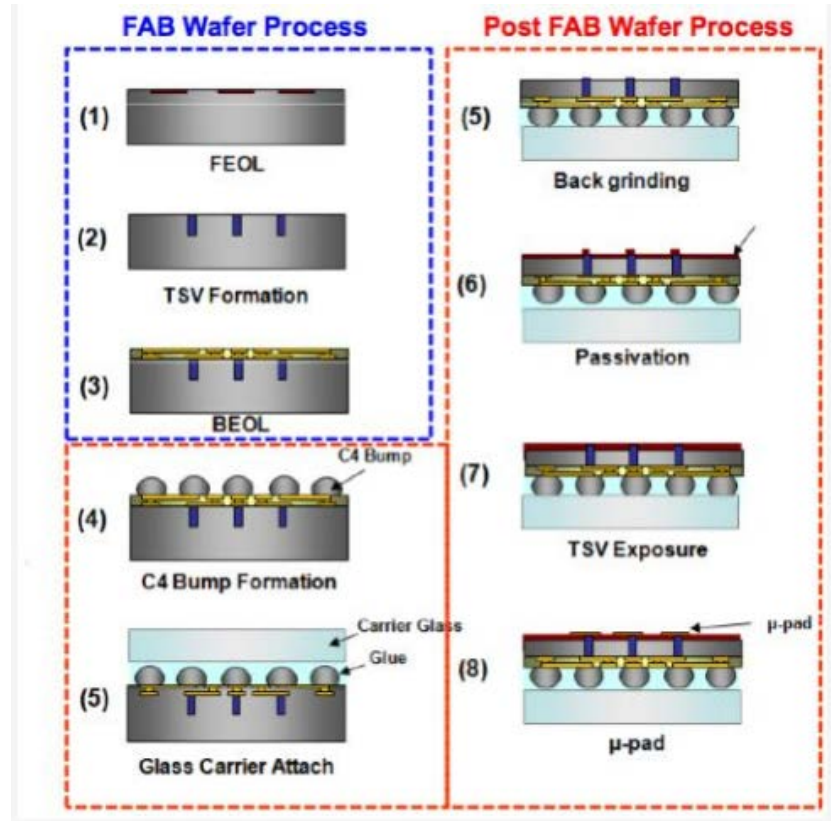


Image Cited from *Shipco Circuits*

Back-up slides

TSV Formation:



Back-up slides

Xilinx Virtex-7 2000T

